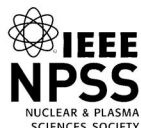


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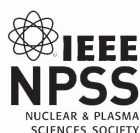
**SELECTED PAPERS FROM THE 2015 CONFERENCE ON RADIATION AND ITS EFFECTS ON
COMPONENTS AND SYSTEMS (RADECS), Moscow, Russia, September 14–18, 2015**

See Part I, p. 1981, for Selected Papers from the 2015 Conference on Radiation and Its Effects on Components and Systems (RADECS) Table of Contents. Selected Papers from the 2015 Conference on Radiation and Its Effects on Components and Systems (RADECS) begin on p. 1986. See Part II, front cover, for Regular Papers Table of Contents. Regular Papers begin on p. 2262.



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